


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585757	<b>Applicant(s)/Patent Under Reexamination</b>  KASAI ET AL.
	<b>Examiner</b>  SHANE FANG	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
257	40	8/11/2009	sf
528	423,424	8/11/2009	sf

SEARCH NOTES		
Search Notes	Date	Examiner
inventor, NPL, and STIC searched	8/11/2009	sf
search updated	3/17/2010	sf

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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